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41,733
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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of:

Applicant : Wiegele et al.
Application No. : 10/620,119
Filed : July 15, 2003
Title : MICRO MIRROR ARRAYS AND MICROSTRUCTURES WITH
SOLDERABLE CONNECTION SITES
Docket No. : 015559-288
Examiner : Wong, Tina Mei Seng
Art Unit : 2874

MAIL STOP AMENDMENT
Commissioner for Patents
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INFORMATION DISCLOSURE STATEMENT

Pursuant to 37 C.F.R. §1.56, the Examiner's attention is directed to the references listed on the attached Information Disclosure Citation. Copies of all foreign patents and non-patent literature references are provided herewith.

It is to be understood that the present submission of art is in no way intended to be a waiver of any arguments or defenses available to the applicant under the rules of the U.S. Patent and Trademark Office and the statutes of the United States.

No fee is required. The Commissioner is authorized to charge any additional fees required by this paper or to credit any overpayment to Deposit Account No. 20-0809.

Respectfully submitted:

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INFORMATION DISCLOSURE CITATION Page 1 of 1	Docket: 015559-288		Appln. No. 10/620,119	
	Applicant: Wiegele et al.			
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U.S. PATENT DOCUMENTS

Examiner		Document No.	Date	Name	Class	Sub	
		2001/041381	11/2001	Choi			
		2001/055146	12/2001	Atobe et al.			
		2002/195673	12/2002	Chou et al.			

FOREIGN PATENT DOCUMENT

Examiner		Document No.	Date	Country	Class	Sub	Trans	
							Y	N

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner:		Date Considered:

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